

FDFMA3N109

Integrated N-Channel PowerTrench® MOSFET and Schottky Diode

General Description

This device is designed specifically as a single package solution for a boost topology in cellular handset and other ultra-portable applications. It features a MOSFET with low input capacitance, total gate charge and onstate resistance, and an independently connected schottky diode with low forward voltage and reverse leakage current to maximize boost efficiency.

The MicroFET 2x2 package offers exceptional thermal performance for its physical size and is well suited to switching and linear mode applications.

Features

MOSFET:

• 2.9 A, 30 V $R_{DS(ON)}$ = 123 m Ω @ V_{GS} = 4.5 V

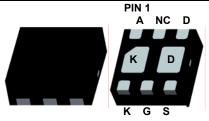
 $R_{DS(ON)}$ = 140 m Ω @ V_{GS} = 3.0 V

 $R_{DS(ON)} = 163 \text{ m}\Omega @ V_{GS} = 2.5 \text{ V}$

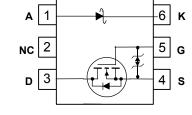
Schottky:

- V_F < 0.46 V @ 500mA
- Low profile 0.8 mm maximum in the new package MicroFET 2x2 mm
- HBM ESD protection level = 1.8kV typical (Note 3)
- RoHS Compliant





MicroFET 2x2



Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units	
V _{DS}	Drain-Source Voltage		30	V	
V _{GS}	Gate-Source Voltage		±12	V	
I _D	Drain Current – Continuous (T _C = 25°C, V _{GS} = 4.5V)		2.9		
	- Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 2.5V$)		2.7	Α	
	– Pulsed		10		
P _D	Power Dissipation for Single Operation	(Note 1a)	1.5	W	
	Power Dissipation for Single Operation	(Note 1b)	0.65	VV	
T_J , T_{STG}	Operating and Storage Temperature		-55 to +150	°C	
V_{RRM}	Schottky Repetitive Peak Reverse Voltage		28	V	
Io	Schottky Average Forward Current		1	Α	

Thermal Characteristics

R _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	83	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	193	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1c)	101	C/VV
R _{θJA}	Thermal Resistance, Junction-to-Ambient	(Note 1d)	228	

Package Marking and Ordering Information

		J : : : : :			
	Device Marking	Device	Reel Size	Tape width	Quantity
_	109	FDFMA3N109	7"	8mm	3000 units

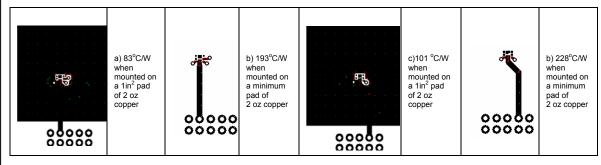
Symbol	Parameter	Test Condit	ions	Min	Тур	Max	Units
Off Char	acteristics			ı			
BV _{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 250$) μ A	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Reference			25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0$) V			1	μА
I _{GSS}	Gate-Body Leakage Current	$V_{GS} = \pm 12 \text{ V}, V_{DS} = 0$) V			±10	μА
On Char	acteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, \qquad I_D = 250$	Ο μΑ	0.4	1.0	1.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Reference	ed to 25°C		-3		mV/°C
		$V_{GS} = 4.5V, I_D = 2.9A$			75	123	
		$V_{GS} = 3.0V, I_D = 2.7A$			84	140]
R _{DS(on)}	Static Drain–Source	$V_{GS} = 2.5V, I_D = 2.5A$			92	163	mΩ
_ = (=)	On–Resistance	$V_{GS} = 4.5V, I_D = 2.9A, T_{CS} = 4.5V$			95	166	ŀ
		$V_{GS} = 3.0V, I_D = 2.7A, T_{CS}$			138 150	203 268	ł
D	Ob a walata wilati a a	$V_{GS} = 2.5V, I_D = 2.5A, T_{CS}$	1 _C = 150 C		150	200	
C _{iss}	Input Capacitance	N 45 N N 6		1	190	220	pF
Coss	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0$ f = 1.0 MHz) V,		30	40	рF
	Reverse Transfer Capacitance	1 - 1.0 MHZ			20		
C _{rss}	Gate Resistance	V _{GS} = 0 V, f = 1.0 I	MHz		4.6	30	pF Ω
		V GS V V, 1 1.01	1711 12		7.0		32
	g Characteristics (Note 2)	V _{DD} = 15 V, I _D = 1 A		T	6	12	no
t _{d(on)}	Turn-On Delay Time Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 1.5 \text{ V}$			8	16	ns
t _r					12	21	ns
t _{d(off)}	Turn-Off Delay Time						ns
t _f	Turn-Off Fall Time	V _{DS} = 15 V, I _D = 2.9	Α		2	4	ns
Q _g	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_D = 2.9$ $V_{GS} = 4.5 \text{ V}$	А,		2.4	3.0	nC
Q _{gs}	Gate–Source Charge	- VGS - 4.5 V			0.35		nC
Q _{gd}	Gate-Drain Charge				0.75		nC
	ource Diode Characteristics			1	1	0.0	1 4
Is	Maximum Continuous Drain–Source	+	Į.			2.9	Α
V_{SD}	Drain–Source Diode Forward Voltage	I _S = 2.0 A		+	0.9	1.2	V
t _{rr}	Diode Reverse Recovery Time	$I_S = 1.1 \text{ A}$ $I_F = 2.9 \text{ A}$			0.8	1.2	ns
Q _{rr}	Diode Reverse Recovery Charge	dI _F /dt = 100 A/µs			2		nC
	Diode Characteristics				I		
_		Т.	= 25°C		10	100	μА
I_R	Reverse Leakage	V _D = 78 V	= 85°C		0.07	4.7	mΑ
\ /	Forward Voltage	Т.	= 25°C	1	0.50	0.57	
V_{F}		$I_F = 1 \text{ A}$ $T_J = 85^{\circ}\text{C}$			0.49	0.60	V
· ·	Forward Voltage	I _E = 500 mA T _J	= 25°C		0.40	0.46	V
V_{F}	i orwaru voltage	T.	= 85°C		0.36	0.43	, v

Electrical Characteristics

T_A = 25°C unless otherwise noted

Notes:

- 1. R_{0JA} is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0JA} is determined by the user's board design.
 - (a) MOSFET R_{0JA} = 83°C/W when mounted on a 1in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
 - (b) MOSFET $R_{\theta JA}$ = 193°C/W when mounted on a minimum pad of 2 oz copper
 - (c) Schottky $R_{\theta JA}$ = 101°C/W when mounted on a 1in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB
 - (d) Schottky $R_{\theta JA}$ = 228°C/W when mounted on a minimum pad of 2 oz copper



Scale 1:1 on letter size paper

- **2.** Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%
- 3: The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics

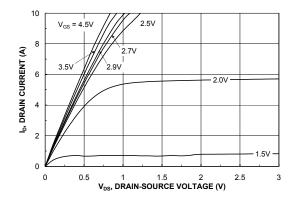


Figure 1. On-Region Characteristics.

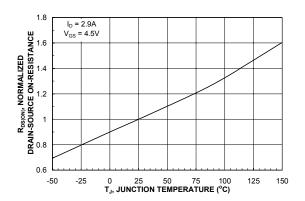


Figure 3. On-Resistance Variation with Temperature.

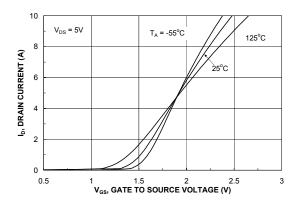


Figure 5. Transfer Characteristics.

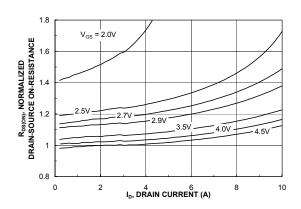


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

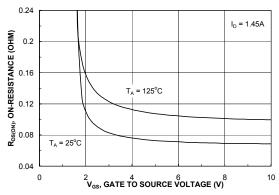


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

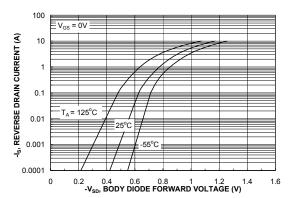
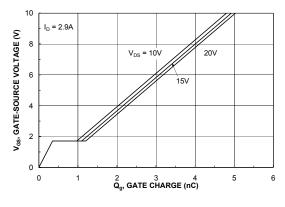


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



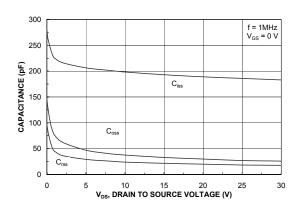
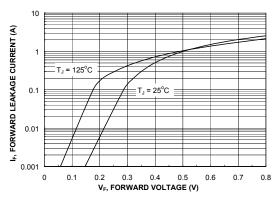


Figure 7. Gate Charge Characteristics.





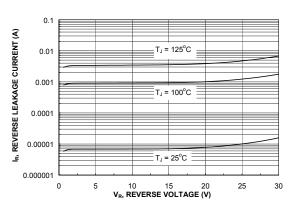


Figure 9. Schottky Diode Forward Voltage.

Figure 10. Schottky Diode Reverse Current.

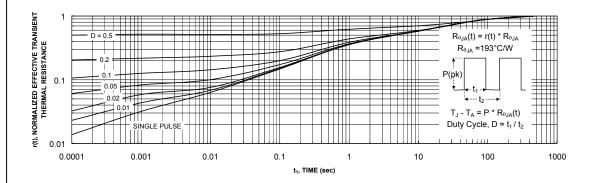
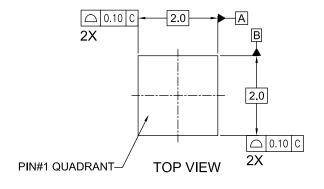
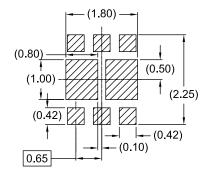


Figure 11. Transient Thermal Response Curve.

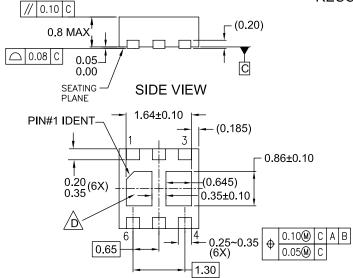
Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN



BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC EXCEPT AS NOTED.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- NON-JEDEC DUAL DAP
- E. DRAWING FILE NAME : MLP06J rev3





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